

<b>Notice of References Cited</b>	Application/Control No. 09/990,279	Applicant(s)/Patent Under Reexamination HONG, HYUNG-KI	
	Examiner A. Sefer	Art Unit 2826	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,570,554	05-2003	Makino et al.	345/102
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 2000-111871	04-2000	Japan	Takabayashi et al.	
	O	JP 11-305211	11-1999	Japan	Akimoto e tal.	
	P	JP 2000-214435	08-2000	Japan	Matsueda	
	Q	JP 2000-162575	06-2000	Japan		
	R	EP 875 880	11-1998	European	Uchida et al	
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

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